Replacement Sheet

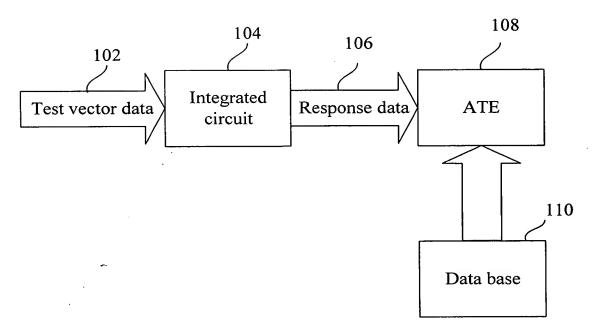
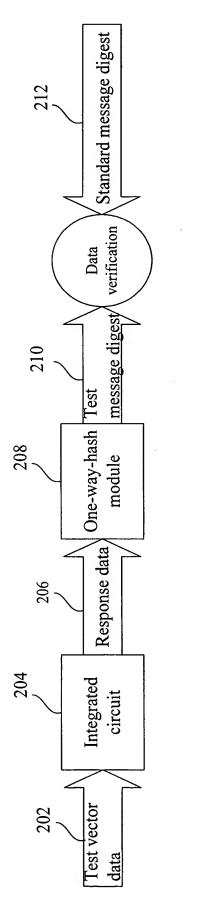


Fig. 1
(Prior Art)

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ACCELERATED TEST METHOD AND SYSTEM
Application No. 10/713,154
Inventor: Yen-Fu LIU
Replacement Sheet



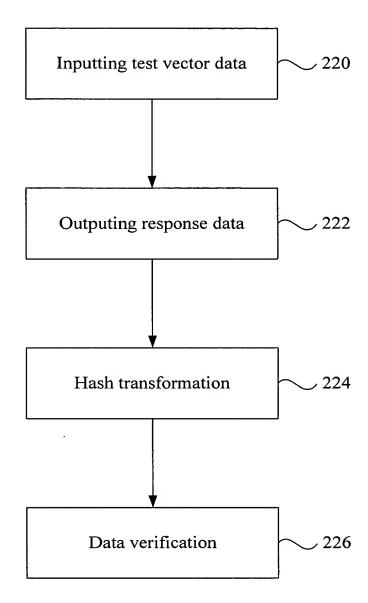


Fig. 2B

ACCELERATED TEST METHOD AND SYSTEM Application No. 10/713,154

Inventor: Yen-Fu LIU Replacement Sheet

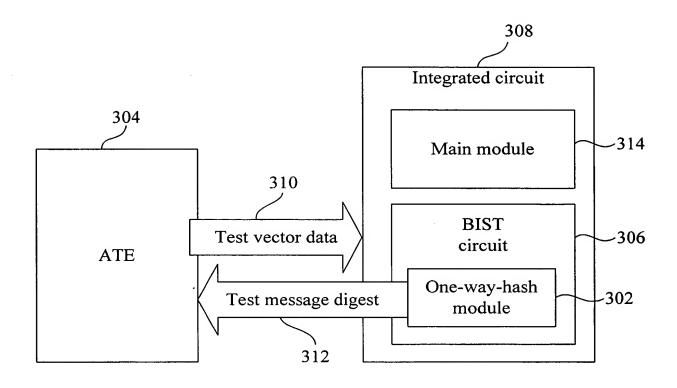


Fig. 3

ACCELERATED TEST METHOD AND SYSTEM Application No. 10/713,154 Inventor: Yen-Fu LIU Replacement Sheet

Integrated circuit 402 416 410 IP 1 Test vector data BIST 418 circuit One-way-hash module -Test message digest 404 424 412 IP 2 Test vector data BIST 420 **ATE** circuit One-way-hash module Test message digest 406 426 414 IP 3 Test vector data BIST 422 circuit One-wayhash Test message digest module 428 408

Fig. 4

ACCELERATED TEST METHOD AND SYSTEM Application No. 10/713,154 Inventor: Yen-Fu LIU Replacement Sheet

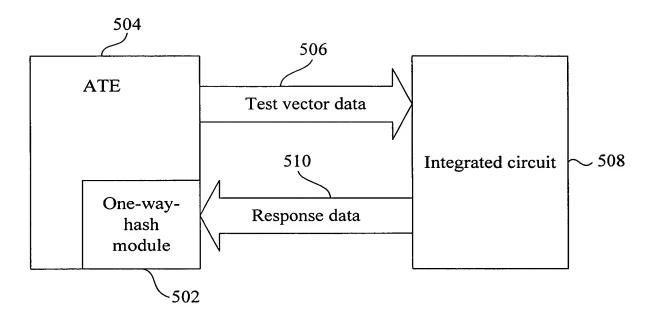


Fig. 5